


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/506,509	OISHI ET AL.	
	Examiner	Art Unit	
	Sikyin Ip	1742	

SEARCHED			
Class	Subclass	Date	Examiner
148	420		
420	407-409	9/29/2007	SI

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	9/29/2007	SI